

NPS Collaborators' Meeting Minutes

Date: November 12, 2020

Time: 9:00AM – 10:00AM

Attendees: Vladimir Berdnikov, Marie Boer, Aaron Brown, Alexandre Camsonne, Rolf Ent, William Gu, Tanja Horn, Charles Hyde, Steven Lassiter, Paulo Medeiros, Hamlet Mkrtchyan, Carlos Munoz-Camacho, Julie Roche, Brad Sawatzky, Vardan Tadevosyan, Bogdan Wojtsekhowski, Stephen Wood, Carlos Yero

1. Detector Frame Assembly

- 1.1. Carlos Munoz-Camacho presented photos of [detector cooling system](#)
 - 1.1.1. Cooling system consists of copper piping and has been leak tested; still requires pressure testing
 - 1.1.2. Chillers have a cooling capacity of 825 W; heat output of detector electronics is ~600 W
- 1.2. Detector arms and rails have been delivered
- 1.3. Cable routing for detector is still in progress
- 1.4. Carlos Munoz-Camacho will provide more information regarding grounding PMTs
- 1.5. Frame still on schedule to be delivered by December 2020 or January 2021

2. DSG Update

- 2.1. Aaron Brown presented [NPS Collaborators' Meeting](#) DSG Update
- 2.2. Mindy Leffel has fabricated 980 of 1100 HV divider cables
- 2.3. No change in shipping status or expected delivery dates for components to fabricate 140' multi-conductor cables
- 2.4. Experienced EPICS communication issues during CAEN HV module ramp testing using CSS-BOY script
 - 2.4.1. Some channels failed to ramp or ramp properly
 - 2.4.2. Debugging issues and exploring options for ways to conduct ramp testing without involving CSS
 - 2.4.3. Brad Sawatzky suggested contacting Wesley Moore as he may have experienced this problem
- 2.5. Investigating procurement of spare Keysight model 34980A mainframe and model 34921A multiplexers

3. Fast Electronics

- 3.1. William Gu gave a presentation about [VME LED driver design](#)
- 3.2. Brad Sawatzky suggested placing VME crate alongside chillers to reduce length of cables

4. Assembly/Checkout

- 4.1. Brad Sawatzky presented draft of [NPS Assembly Floor Space Layout](#)
 - 4.1.1. Floor plan shows potential locations for detector elements during assembly in the Test Lab or ESB